AMD Xilinx - XC6VHX250T-1FF1154I Datasheet

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The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	19680
Number of Logic Elements/Cells	251904
Total RAM Bits	18579456
Number of I/O	320
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1156-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vhx250t-1ff1154i

Table 2: **Recommended Operating Conditions**

Symbol	Description	Min	Max	Units
V_{CCINT}	Internal supply voltage relative to GND for all devices except -1L devices.	0.95	1.05	V
	For -1L commercial temperature range devices: internal supply voltage relative to GND, T_j = 0°C to +85°C	0.87	0.93	V
	For -1L industrial temperature range devices: internal supply voltage relative to GND, T_j = –40°C to +100°C	0.91	0.97	V
V_{CCAUX}	Auxiliary supply voltage relative to GND	2.375	2.625	V
V_{CCO}(1)(2)(3)	Supply voltage relative to GND	1.14	2.625	V
V_{IN}	2.5V supply voltage relative to GND	GND – 0.20	2.625	V
	2.5V and below supply voltage relative to GND	GND – 0.20	V_{CCO} + 0.2	V
I_{IN}(5)	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	10	mA
V_{BATT}(6)	Battery voltage relative to GND	1.0	2.5	V
V_{FS}(7)	External voltage supply for eFUSE programming	2.375	2.625	V
T_j	Junction temperature operating range for commercial (C) temperature devices	0	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	100	°C
	Junction temperature operating range for industrial (I) temperature devices	–40	100	°C
	Junction temperature operating range for military (M) temperature devices	–55	125	°C

Notes:

1. Configuration data is retained even if V_{CCO} drops to 0V.
2. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, and 2.5V.
3. The configuration supply voltage V_{CC_CONFIG} is also known as V_{CCO_0}.
4. All voltages are relative to ground.
5. A total of 100 mA per bank should not be exceeded.
6. V_{BATT} is required only when using bitstream encryption. If battery is not used, connect V_{BATT} to either ground or V_{CCAUX}.
7. During eFUSE programming, V_{FS} must be within the recommended operating range and T_j = +15°C to +85°C. Otherwise, V_{FS} can be connected to GND.

Table 3: **DC Characteristics Over Recommended Operating Conditions (1)(2)**

Symbol	Description	Min	Typ	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	–	–	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	2.0	–	–	V
I_{REF}	V_{REF} leakage current per pin	–	–	10	µA
I_L	Input or output leakage current per pin (sample-tested)	–	–	10	µA
C_{IN}(3)	Die input capacitance at the pad	–	–	8	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 2.5V	20	–	80	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.8V	8	–	40	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.5V	5	–	30	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.2V	1	–	20	µA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 2.5V	3	–	80	µA
I_{BATT}	Battery supply current	–	–	150	nA
n	Temperature diode ideality factor	–	1.0002	–	n
r	Series resistance	–	5	–	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Maximum value specified for worst case process at 25°C.
3. This measurement represents the die capacitance at the pad, not including the package.

Important Note

Typical values for quiescent supply current are specified at nominal voltage, 85°C junction temperatures (T_j). Xilinx recommends analyzing static power consumption at T_j = 85°C because the majority of designs operate near the high end of the commercial temperature range. Quiescent supply current is specified by speed grade for Virtex-6 devices. Use the XPower™ Estimator (XPE) spreadsheet tool (download at http://www.xilinx.com/power) to calculate static power consumption for conditions other than those specified in Table 4.

Table 4: **Typical Quiescent Supply Current**

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M)(2)	-1L (C)	-1L (I)(1)	
I_{CCINTQ}	Quiescent V_{CCINT} supply current	XC6VLX75T	927	927	927	N/A	656	741	mA
		XC6VLX130T	1563	1563	1563	N/A	1102	1245	mA
		XC6VLX195T	2059	2059	2059	N/A	1441	1628	mA
		XC6VLX240T	2478	2478	2478	N/A	1733	1957	mA
		XC6VLX365T	3001	3001	3001	N/A	2092	2363	mA
		XC6VLX550T(3)	N/A	4515	4515	N/A	3147	3555	mA
		XC6VLX760(3)	N/A	5094	5094	N/A	3471	3921	mA
		XC6VSX315T	3476	3476	3476	N/A	2409	2721	mA
		XC6VSX475T(3)	N/A	5227	5227	N/A	3622	4091	mA
		XC6VHX250T	2906	2906	2906	N/A	N/A	N/A	mA
		XC6VHX255T	2746	2746	2746	N/A	N/A	N/A	mA
		XC6VHX380T(4)	4160	4160	4160	N/A	N/A	N/A	mA
		XC6VHX565T(5)	N/A	5207	5207	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1563	N/A	1563	N/A	1245	mA
		XQ6VLX240T	N/A	2478	N/A	2478	N/A	1957	mA
		XQ6VLX550T(7)	N/A	N/A	N/A	4515	N/A	3555	mA
		XQ6VSX315T	N/A	3476	N/A	3476	N/A	2721	mA
		XQ6VSX475T(7)	N/A	N/A	N/A	5227	N/A	4091	mA

Table 4: **Typical Quiescent Supply Current *(Cont'd)***

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M)(2)	-1L (C)	-1L (I)(1)	
I_{CCAUXQ}	Quiescent V_{CCAUX} supply current	XC6VLX75T	45	45	45	N/A	45	45	mA
		XC6VLX130T	75	75	75	N/A	75	75	mA
		XC6VLX195T	113	113	113	N/A	113	113	mA
		XC6VLX240T	135	135	135	N/A	135	135	mA
		XC6VLX365T	191	191	191	N/A	191	191	mA
		XC6VLX550T(3)	N/A	286	286	N/A	286	286	mA
		XC6VLX760(3)	N/A	387	387	N/A	387	387	mA
		XC6VSX315T	186	186	186	N/A	186	186	mA
		XC6VSX475T(3)	N/A	279	279	N/A	279	279	mA
		XC6VHX250T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX255T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX380T(4)	227	227	227	N/A	N/A	N/A	mA
		XC6VHX565T(5)	N/A	315	315	N/A	N/A	N/A	mA
		XQ6VLX130T(6)	N/A	75	N/A	75	N/A	75	mA
		XQ6VLX240T(6)	N/A	135	N/A	135	N/A	135	mA
		XQ6VLX550T(7)	N/A	N/A	N/A	286	N/A	286	mA
		XQ6VSX315T(6)	N/A	186	N/A	186	N/A	186	mA
		XQ6VSX475T(7)	N/A	N/A	N/A	279	N/A	279	mA

Notes:

1. Typical values are specified at nominal voltage, 85°C junction temperatures (T_j). -1 and -2 industrial (I) grade devices have the same typical values as commercial (C) grade devices at 85°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. -1L industrial temperature range devices have the values specified in this column.
2. Use the XPE tool to calculate 125°C values for -1M temperature range devices.
3. The -2E extended temperature range (T_j = 0°C to +100°C) is only available in these devices. The -2I temperature range (T_j = –40°C to +100°C) is available for all other devices except the XC6VHX565T.
4. The XC6VHX380T is available with both -2E and -2I temperature ranges.
5. The XC6VHX565T is only available in the following temperature ranges: -1C, -1I, -2C, and -2E.
6. The XQ6VLX130T, XQ6VLX240T, and XQ6VSX315T are available in -2I, -1I, -1M, and -1LI temperature ranges.
7. The XQ6VLX550T and the XQ6VSX475T are only available in -1I and -1LI temperature ranges.
8. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
9. If DCI or differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPE or XPower Analyzer (XPA) tools.

Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on sequence and ramp rate of the power supply.

The recommended power-on sequence for Virtex-6 devices is V_{CCINT}, V_{CCAUX}, and V_{CCO} to meet the power-up current requirements listed in Table 5. V_{CCINT} can be powered up or down at any time, but power up current specifications can vary from Table 5. The device will have no physical damage or reliability concerns if V_{CCINT}, V_{CCAUX}, and V_{CCO} sequence cannot be followed.

If the recommended power-up sequence cannot be followed and the I/Os must remain 3-stated throughout configuration, then V_{CCAUX} must be powered prior to V_{CCO} or V_{CCAUX} and V_{CCO} must be powered by the same supply. Similarly, for power-down, the reverse V_{CCAUX} and V_{CCO} sequence is recommended if the I/Os are to remain 3-stated.

The GTH transceiver supplies must be powered using a MGTHAVCC, MGTHAVCCRX, MGTHAVCCPLL, and MGTHAVTT sequence. There are no sequencing requirement for these supplies with respect to the other FPGA supply voltages. For more detail see Table 27: *GTH Transceiver Power Supply Sequencing*. There are no sequencing requirements for the GTX transceivers power supplies.

Table 5 shows the minimum current, in addition to I_{CCQ}, that are required by Virtex-6 devices for proper power-on and configuration. If the current minimums shown in Table 4 and Table 5 are met, the device powers on after all three supplies have passed through their power-on reset threshold voltages. The FPGA must be configured after applying V_{CCINT}, V_{CCAUX}, and V_{CCO} for the appropriate configuration banks. Once initialized and configured, use the XPE tools to estimate current drain on these supplies.

Table 5: **Power-On Current for Virtex-6 Devices**

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	Units
	Typ(1)	Typ(1)	Typ(1)	
XC6VLX75T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 10	I_{CCOQ} + 30 mA per bank	mA
XC6VLX130T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 10	I_{CCOQ} + 30 mA per bank	mA
XC6VLX195T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VLX240T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VLX365T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VLX550T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VLX760	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VSX315T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VSX475T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 50	I_{CCOQ} + 30 mA per bank	mA
XC6VHX250T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VHX255T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VHX380T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VHX565T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XQ6VLX130T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 30 mA per bank	mA
XQ6VLX240T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 30 mA per bank	mA
XQ6VLX550T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 30 mA per bank	mA
XQ6VSX315T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 40 mA per bank	mA
XQ6VSX475T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 40 mA per bank	mA

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at http://www.xilinx.com/power) to calculate maximum power-on currents.

Table 6: **Power Supply Ramp Time**

Symbol	Description	Ramp Time	Units
V_{CCINT}	Internal supply voltage relative to GND	0.20 to 50.0	ms
V_{CCO}	Output drivers supply voltage relative to GND	0.20 to 50.0	ms
V_{CCAUX}	Auxiliary supply voltage relative to GND	0.20 to 50.0	ms

SelectIO™ DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 7: **SelectIO DC Input and Output Levels**

I/O Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVCMOS25, LVDCI25	–0.3	0.7	1.7	V_{CCO} + 0.3	0.4	V_{CCO} – 0.4	Note(3)	Note(3)
LVCMOS18, LVDCI18	–0.3	35% V_{CCO}	65% V_{CCO}	V_{CCO} + 0.3	0.45	V_{CCO} – 0.45	Note(4)	Note(4)
LVCMOS15, LVDCI15	–0.3	35% V_{CCO}	65% V_{CCO}	V_{CCO} + 0.3	25% V_{CCO}	75% V_{CCO}	Note(4)	Note(4)
LVCMOS12	–0.3	35% V_{CCO}	65% V_{CCO}	V_{CCO} + 0.3	25% V_{CCO}	75% V_{CCO}	Note(5)	Note(5)
HSTL I_12	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	V_{CCO} + 0.3	25% V_{CCO}	75% V_{CCO}	6.3	6.3
HSTL I(2)	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	V_{CCO} + 0.3	0.4	V_{CCO} – 0.4	8	–8
HSTL II(2)	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	V_{CCO} + 0.3	0.4	V_{CCO} – 0.4	16	–16
HSTL III(2)	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	V_{CCO} + 0.3	0.4	V_{CCO} – 0.4	24	–8
DIFF HSTL I(2)	–0.3	50% V_{CCO} – 0.1	50% V_{CCO} + 0.1	V_{CCO} + 0.3	–	–	–	–
DIFF HSTL II(2)	–0.3	50% V_{CCO} – 0.1	50% V_{CCO} + 0.1	V_{CCO} + 0.3	–	–	–	–
SSTL2 I	–0.3	V_{REF} – 0.15	V_{REF} + 0.15	V_{CCO} + 0.3	V_{TT} – 0.61	V_{TT} + 0.61	8.1	–8.1
SSTL2 II	–0.3	V_{REF} – 0.15	V_{REF} + 0.15	V_{CCO} + 0.3	V_{TT} – 0.81	V_{TT} + 0.81	16.2	–16.2
DIFF SSTL2 I	–0.3	50% V_{CCO} – 0.15	50% V_{CCO} + 0.15	V_{CCO} + 0.3	–	–	–	–
DIFF SSTL2 II	–0.3	50% V_{CCO} – 0.15	50% V_{CCO} + 0.15	V_{CCO} + 0.3	–	–	–	–
SSTL18 I	–0.3	V_{REF} – 0.125	V_{REF} + 0.125	V_{CCO} + 0.3	V_{TT} – 0.47	V_{TT} + 0.47	6.7	–6.7
SSTL18 II	–0.3	V_{REF} – 0.125	V_{REF} + 0.125	V_{CCO} + 0.3	V_{TT} – 0.60	V_{TT} + 0.60	13.4	–13.4
DIFF SSTL18 I	–0.3	50% V_{CCO} – 0.125	50% V_{CCO} + 0.125	V_{CCO} + 0.3	–	–	–	–
DIFF SSTL18 II	–0.3	50% V_{CCO} – 0.125	50% V_{CCO} + 0.125	V_{CCO} + 0.3	–	–	–	–
SSTL15	–0.3	V_{REF} – 0.1	V_{REF} + 0.1	V_{CCO} + 0.3	V_{TT} – 0.175	V_{TT} + 0.175	14.3	14.3

Notes:

1. Tested according to relevant specifications.
2. Applies to both 1.5V and 1.8V HSTL.
3. Using drive strengths of 2, 4, 6, 8, 12, 16, or 24 mA.
4. Using drive strengths of 2, 4, 6, 8, 12, or 16 mA.
5. Supported drive strengths of 2, 4, 6, or 8 mA.
6. For detailed interface specific DC voltage levels, see UG361: *Virtex-6 FPGA SelectIO Resources User Guide*.

Table 16: **GTX Transceiver Quiescent Supply Current (per Lane) (1)(2)(3)**

Symbol	Description	Typ(4)	Max	Units
$I_{MGTAVTTQ}$	Quiescent MGTAVTT supply current for one GTX transceiver	0.9	Note 2	mA
$I_{MGTAVCCQ}$	Quiescent MGTAVCC supply current for one GTX transceiver	3.5		mA

Notes:

1. Device powered and unconfigured.
2. Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.
3. GTX transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTX transceivers.
4. Typical values are specified at nominal voltage, 25°C.

GTX Transceiver DC Input and Output Levels

Table 17 summarizes the DC output specifications of the GTX transceivers in Virtex-6 FPGAs. Consult UG366: *Virtex-6 FPGA GTX Transceivers User Guide* for further details.

Table 17: **GTX Transceiver DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV_{PPIN}	Differential peak-to-peak input voltage	External AC coupled ≤ 4.25 Gb/s	125	–	2000	mV
		External AC coupled > 4.25 Gb/s	175	–	2000	mV
V_{IN}	Absolute input voltage	DC coupled MGTAVTT = 1.2V	–400	–	MGTAVTT	mV
V_{CMIN}	Common mode input voltage	DC coupled MGTAVTT = 1.2V	–	2/3 MGTAVTT	–	mV
DV_{PPOUT}	Differential peak-to-peak output voltage(1)	Transmitter output swing is set to maximum setting	–	–	1000	mV
$V_{CMOUTDC}$	DC common mode output voltage.	Equation based	MGTAVTT – DV_{PPOUT}/4			mV
R_{IN}	Differential input resistance		80	100	130	Ω
R_{OUT}	Differential output resistance		80	100	120	Ω
T_{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	8	ps
C_{EXT}	Recommended external AC coupling capacitor(2)		–	100	–	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in UG366: *Virtex-6 FPGA GTX Transceivers User Guide* and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

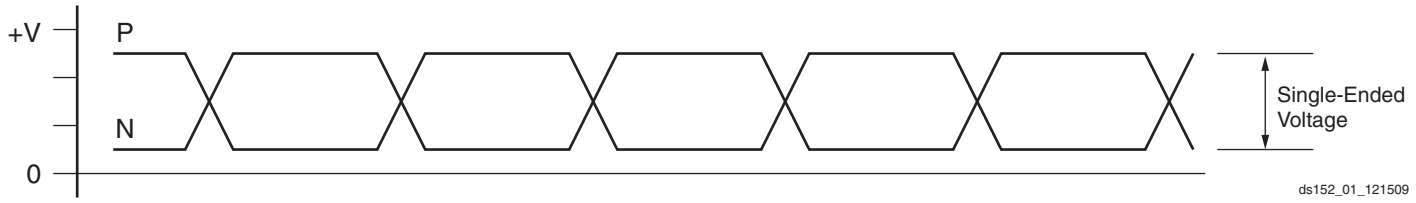

Figure 1: **Single-Ended Peak-to-Peak Voltage**

GTH Transceiver Specifications

GTH Transceiver DC Characteristics

Table 25: **Absolute Maximum Ratings for GTH Transceivers(1)**

Symbol	Description	Min	Max	Units
MGTHAVCC	Analog supply voltage for the GTH transmitter, receiver, and common analog circuits	–0.5	1.125	V
MGTHAVCCRX	Analog supply voltage for the GTH receiver circuits and common analog circuits	–0.5	1.125	V
MGTHAVTT	Analog supply voltage for the GTH transmitter termination circuits	–0.5	1.32	V
MGTHAVCCPLL	Analog supply voltage for the GTH receiver and PLL circuits	–0.5	1.935	V
V_{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	–0.5	1.125	V
$V_{MGTREFCLK}$	Reference clock absolute input voltage	–0.5	1.935	V

Notes:

1. Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.

Table 26: **Recommended Operating Conditions for GTH Transceivers (1)(2)**

Symbol	Description	Min	Typ	Max	Units
MGTHAVCC	Analog supply voltage for the GTH transmitter, receiver, and common analog circuits	1.075	1.1	1.125	V
MGTHAVCCRX	Analog supply voltage for the GTH receiver circuits and common analog circuits	1.075	1.1	1.125	V
MGTHAVTT	Analog supply voltage for the GTH transmitter termination circuits	1.140	1.2	1.26	V
MGTHAVCCPLL	Analog supply voltage for the GTH receiver and PLL circuit	1.710	1.8	1.89	V

Notes:

1. Each voltage listed requires the filter circuit described in UG371: *Virtex-6 FPGA GTH Transceivers User Guide*.
2. Voltages are specified for the temperature range of T_j = –40°C to +100°C.

Table 27: **GTH Transceiver Power Supply Sequencing (1)(2)(3)**

Symbol	Description	Min	Max	Units
$T_{HAVCC2HAVCCRX}$	Maximum time between powering MGTHAVCC to when MGTHAVCCRX must be powered.	0	5	ms
$T_{HAVCCRX2HAVCCPLL}$	Minimum time between powering MGTHAVCCRX to when MGTHAVCCPLL can be powered.	10	–	µs
$T_{HAVCCRX2HAVTT}$	Minimum time between powering MGTHAVCCRX to when MGTHAVTT can be powered.	10	–	µs

Notes:

1. MGTHAVCCRX must be powered simultaneously or within $T_{HAVCC2HAVCCRX}$ of MGTHAVCC, but it must not precede MGTHAVCC.
2. MGTHAVCC and MGTHAVCCRX must be powered before MGTHAVCCPLL and MGTHAVTT. This minimum time is defined by $T_{HAVCCRX2HAVCCPLL}$ and $T_{HAVCCRX2HAVTT}$.
3. At any time, the condition of MGTHAVCC being present and MGTHAVCCRX not being present should not occur for more than the maximum $T_{HAVCC2HAVCCRX}$.

Figure 4 shows the timing parameters in Table 27.

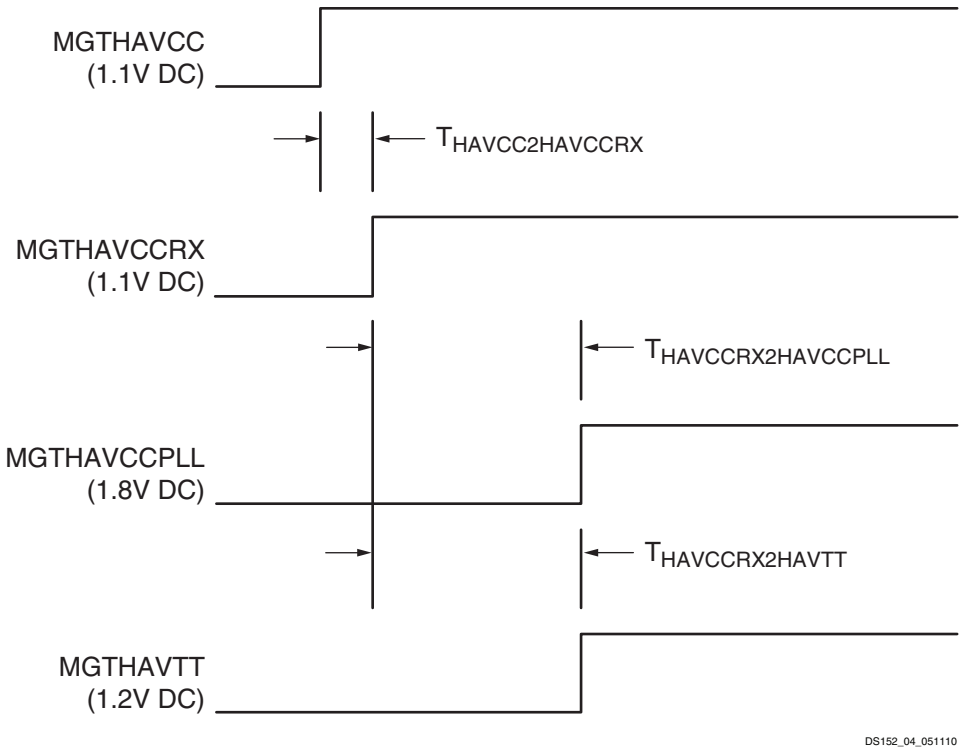

Figure 4: **GTH Transceiver Power Supply Power-On Sequencing**

Table 28: **GTH Transceiver Supply Current**

Symbol	Description	Typ(1)	Max	Units
$I_{MGTHAVCC}$	MGTHAVCC supply current for one GTH Quad (4 lanes)	571	Note 2	mA
$I_{MGTHAVCCRX}$	MGTHAVCCRX supply current for a GTH Quad (4 lanes)	254	Note 2	mA
$I_{MGTHAVTT}$	MGTHAVTT supply current for one GTH Quad (4 lanes)	93	Note 2	mA
$I_{MGTHAVCCPLL}$	MGTHAVCCPLL supply current for one GTH Quad (4 lanes)	219	Note 2	mA
$MGTR_{REF}$	Precision reference resistor for internal calibration termination	1000.0 ± 1% tolerance		Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C, with a 10.3125 Gb/s line rate.
2. Values for currents other than the values specified in this table can be obtained by using the XPower Estimator (XPE) or XPower Analyzer (XPA) tools.

Table 29: **GTH Transceiver Quiescent Supply Current(1)(2)**

Symbol	Description	Typ(3)	Max	Units
$I_{MGTHAVCCQ}$	Quiescent MGTHAVCC Supply Current for one GTH Quad (4 lanes)	65	Note 4	mA
$I_{MGTHAVCCRXQ}$	Quiescent MGTHAVCCRX Supply Current for one GTH Quad (4 lanes)	17	Note 4	mA
$I_{MGTHAVTTQ}$	Quiescent MGTHAVTT Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA
$I_{MGTHAVCCPLLQ}$	Quiescent MGTHAVCCPLL Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA

Notes:

1. Device powered and unconfigured.
2. GTH transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTH transceivers.
3. Typical values are specified at nominal voltage, 25°C.
4. Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.

GTH Transceiver Switching Characteristics

Consult UG371: *Virtex-6 FPGA GTH Transceivers User Guide* for further information.

Table 32: **GTH Transceiver Maximum Data Rate and PLL Frequency Range**

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F_{GTHMAX}	Maximum GTH transceiver data rate	PLL Output Divider = 1	11.182	11.182	10.32	Gb/s
		PLL Output Divider = 4	2.795	2.795	2.58	Gb/s
F_{GTHMIN}	Minimum GTH transceiver data rate(1)	PLL Output Divider = 1	9.92	9.92	9.92	Gb/s
		PLL Output Divider = 4	2.48	2.48	2.48	Gb/s
$F_{GPLLMAX}$	Maximum GTH PLL frequency		5.591	5.591	5.16	GHz
$F_{GPLLMIN}$	Minimum GTH PLL frequency		4.96	4.96	4.96	GHz

Notes:

1. Lower data rates can be achieved using FPGA logic based oversampling designs.

Table 33: **GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics**

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
$F_{GTHDRPCLK}$	GTHDRPCLK maximum frequency	70	70	60	MHz

Table 34: **GTH Transceiver Reference Clock Switching Characteristics**

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-1 speed grade	150	–	645	MHz
		-2 and -3 speed grades	150	–	700	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	CLK	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	2	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	20	µs

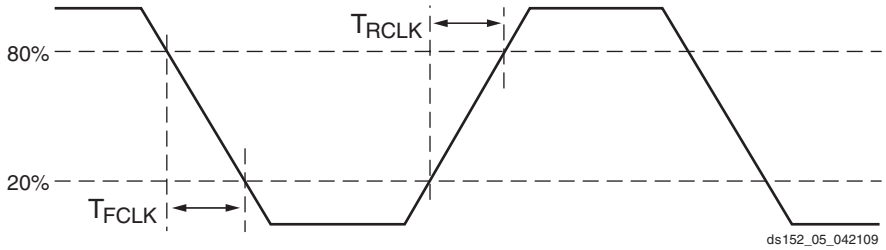

Figure 5: **Reference Clock Timing Parameters**

IOB Pad Input/Output/3-State Switching Characteristics

Table 44 (for commercial (XC) Virtex-6 devices) and Table 45 (for the Defense-grade (XQ) Virtex-6 devices) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.

T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.

T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer.

Table 46 summarizes the value of T_{IOTPHZ}. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state).

Table 44: **IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices**

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
LVDS_25	0.85	0.94	1.09	1.08	1.45	1.54	1.68	1.62	1.45	1.54	1.68	1.62	ns
LVDSEXT_25	0.85	0.94	1.09	1.08	1.53	1.65	1.84	1.73	1.53	1.65	1.84	1.73	ns
HT_25	0.85	0.94	1.09	1.08	1.51	1.62	1.78	1.69	1.51	1.62	1.78	1.69	ns
BLVDS_25	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.65	1.39	1.50	1.67	1.65	ns
RSDS_25 (point to point)	0.85	0.94	1.09	1.08	1.45	1.54	1.68	1.62	1.45	1.54	1.68	1.62	ns
HSTL_I	0.81	0.91	1.06	1.06	1.45	1.56	1.73	1.71	1.45	1.56	1.73	1.71	ns
HSTL_II	0.81	0.91	1.06	1.06	1.44	1.56	1.74	1.72	1.44	1.56	1.74	1.72	ns
HSTL_III	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
HSTL_I_18	0.81	0.91	1.06	1.06	1.47	1.58	1.75	1.72	1.47	1.58	1.75	1.72	ns
HSTL_II_18	0.81	0.91	1.06	1.06	1.50	1.62	1.81	1.78	1.50	1.62	1.81	1.78	ns
HSTL_III_18	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
SSTL2_I	0.81	0.91	1.06	1.06	1.49	1.60	1.77	1.74	1.49	1.60	1.77	1.74	ns
SSTL2_II	0.81	0.91	1.06	1.06	1.42	1.54	1.72	1.71	1.42	1.54	1.72	1.71	ns
SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
LVCMOS25, Slow, 2 mA	0.51	0.57	0.66	0.70	5.09	5.46	6.01	5.63	5.09	5.46	6.01	5.63	ns
LVCMOS25, Slow, 4 mA	0.51	0.57	0.66	0.70	3.30	3.49	3.79	3.65	3.30	3.49	3.79	3.65	ns
LVCMOS25, Slow, 6 mA	0.51	0.57	0.66	0.70	2.62	2.81	3.08	2.95	2.62	2.81	3.08	2.95	ns
LVCMOS25, Slow, 8 mA	0.51	0.57	0.66	0.70	2.21	2.41	2.72	2.59	2.21	2.41	2.72	2.59	ns
LVCMOS25, Slow, 12 mA	0.51	0.57	0.66	0.70	1.80	1.95	2.17	2.10	1.80	1.95	2.17	2.10	ns
LVCMOS25, Slow, 16 mA	0.51	0.57	0.66	0.70	1.89	2.05	2.29	2.21	1.89	2.05	2.29	2.21	ns
LVCMOS25, Slow, 24 mA	0.51	0.57	0.66	0.70	1.68	1.82	2.02	1.98	1.68	1.82	2.02	1.98	ns
LVCMOS25, Fast, 2 mA	0.51	0.57	0.66	0.70	5.12	5.49	6.04	5.62	5.12	5.49	6.04	5.62	ns
LVCMOS25, Fast, 4 mA	0.51	0.57	0.66	0.70	3.28	3.50	3.82	3.65	3.28	3.50	3.82	3.65	ns
LVCMOS25, Fast, 6 mA	0.51	0.57	0.66	0.70	2.56	2.73	2.99	2.88	2.56	2.73	2.99	2.88	ns
LVCMOS25, Fast, 8 mA	0.51	0.57	0.66	0.70	2.11	2.33	2.65	2.53	2.11	2.33	2.65	2.53	ns
LVCMOS25, Fast, 12 mA	0.51	0.57	0.66	0.70	1.74	1.88	2.08	2.03	1.74	1.88	2.08	2.03	ns
LVCMOS25, Fast, 16 mA	0.51	0.57	0.66	0.70	1.77	1.92	2.13	2.08	1.77	1.92	2.13	2.08	ns

Table 44: **IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
LVDCI_DV2_25	0.51	0.57	0.66	0.70	1.71	1.83	2.01	2.00	1.71	1.83	2.01	2.00	ns
LVDCI_DV2_18	0.55	0.61	0.71	0.73	1.69	1.81	2.00	1.98	1.69	1.81	2.00	1.98	ns
LVDCI_DV2_15	0.64	0.73	0.85	0.85	1.68	1.77	1.91	1.98	1.68	1.77	1.91	1.98	ns
LVPECL_25	0.85	0.94	1.09	1.08	1.38	1.49	1.65	1.64	1.38	1.49	1.65	1.64	ns
HSTL_I_12	0.81	0.91	1.06	1.06	1.48	1.60	1.78	1.74	1.48	1.60	1.78	1.74	ns
HSTL_I_DCI	0.81	0.91	1.06	1.06	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns
HSTL_II_DCI	0.81	0.91	1.06	1.06	1.37	1.49	1.68	1.66	1.37	1.49	1.68	1.66	ns
HSTL_II_T_DCI	0.81	0.91	1.06	1.06	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns
HSTL_III_DCI	0.81	0.91	1.06	1.06	1.34	1.45	1.62	1.61	1.34	1.45	1.62	1.61	ns
HSTL_I_DCI_18	0.81	0.91	1.06	1.06	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
HSTL_II_DCI_18	0.81	0.91	1.06	1.06	1.36	1.46	1.62	1.59	1.36	1.46	1.62	1.59	ns
HSTL_II _T_DCI_18	0.81	0.91	1.06	1.06	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
HSTL_III_DCI_18	0.81	0.91	1.06	1.06	1.43	1.54	1.69	1.67	1.43	1.54	1.69	1.67	ns
DIFF_HSTL_I_18	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.72	1.47	1.58	1.75	1.72	ns
DIFF_HSTL_I_DCI_18	0.85	0.94	1.09	1.08	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
DIFF_HSTL_I	0.85	0.94	1.09	1.08	1.45	1.56	1.73	1.71	1.45	1.56	1.73	1.71	ns
DIFF_HSTL_I_DCI	0.85	0.94	1.09	1.08	1.40	1.50	1.66	1.64	1.40	1.50	1.66	1.64	ns
DIFF_HSTL_II_18	0.85	0.94	1.09	1.08	1.50	1.62	1.81	1.78	1.50	1.62	1.81	1.78	ns
DIFF_HSTL_II_DCI_18	0.85	0.94	1.09	1.08	1.36	1.46	1.62	1.59	1.36	1.46	1.62	1.59	ns
DIFF_HSTL_II _T_DCI_18	0.85	0.94	1.09	1.08	1.42	1.53	1.68	1.66	1.42	1.53	1.68	1.66	ns
DIFF_HSTL_II	0.85	0.94	1.09	1.08	1.44	1.56	1.74	1.72	1.44	1.56	1.74	1.72	ns
DIFF_HSTL_II_DCI	0.85	0.94	1.09	1.08	1.37	1.49	1.68	1.66	1.37	1.49	1.68	1.66	ns
SSTL2_I_DCI	0.81	0.91	1.06	1.06	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns
SSTL2_II_DCI	0.81	0.91	1.06	1.06	1.39	1.50	1.67	1.69	1.39	1.50	1.67	1.69	ns
SSTL2_II_T_DCI	0.81	0.91	1.06	1.06	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns
SSTL18_I	0.81	0.91	1.06	1.06	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns
SSTL18_II	0.81	0.91	1.06	1.06	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns
SSTL18_I_DCI	0.81	0.91	1.06	1.06	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
SSTL18_II_DCI	0.81	0.91	1.06	1.06	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns
SSTL18_II_T_DCI	0.81	0.91	1.06	1.06	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
DIFF_SSTL2_I	0.85	0.94	1.09	1.08	1.49	1.60	1.77	1.74	1.49	1.60	1.77	1.74	ns
DIFF_SSTL2_I_DCI	0.85	0.94	1.09	1.08	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns
DIFF_SSTL2_II	0.85	0.94	1.09	1.08	1.42	1.54	1.72	1.71	1.42	1.54	1.72	1.71	ns
DIFF_SSTL2_II_DCI	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.69	1.39	1.50	1.67	1.69	ns
DIFF_SSTL2_II_T_DCI	0.85	0.94	1.09	1.08	1.42	1.53	1.70	1.68	1.42	1.53	1.70	1.68	ns

Table 45: **IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices *(Cont'd)***

I/O Standard	T_{IOPI}			T_{IOOP}			T_{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
DIFF_SSTL18_II	0.94	1.09	1.08	1.50	2.27	1.66	1.50	2.27	1.66	ns
DIFF_SSTL18_II_DCI	0.94	1.09	1.08	1.47	2.20	1.62	1.47	2.20	1.62	ns
DIFF_SSTL18_II_T_DCI	0.94	1.09	1.08	1.51	2.30	1.65	1.51	2.30	1.65	ns
DIFF_SSTL15	0.91	1.06	1.06	1.54	2.25	1.69	1.54	2.25	1.69	ns
DIFF_SSTL15_DCI	0.91	1.06	1.06	1.52	2.25	1.66	1.52	2.25	1.66	ns
DIFF_SSTL15_T_DCI	0.91	1.06	1.06	1.52	2.25	1.66	1.52	2.25	1.66	ns

Table 46: **IOB 3-state ON Output Switching Characteristics (T_{IOTPHZ})**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T_{IOTPHZ}	T input to Pad high-impedance	0.86	0.92	0.99	0.99	ns

I/O Standard Adjustment Measurement Methodology

Input Delay Measurements

Table 47 shows the test setup parameters used for measuring input delay.

Table 47: **Input Delay Measurement Methodology**

Description	I/O Standard Attribute	V_L (1)(2)	V_H (1)(2)	V_{MEAS} (1)(4)(5)	V_{REF} (1)(3)(5)
LVCMOS, 2.5V	LVCMOS25	0	2.5	1.25	–
LVCMOS, 1.8V	LVCMOS18	0	1.8	0.9	–
LVCMOS, 1.5V	LVCMOS15	0	1.5	0.75	–
HSTL (High-Speed Transceiver Logic), Class I & II	HSTL_I, HSTL_II	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.75
HSTL, Class III	HSTL_III	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.90
HSTL, Class I & II, 1.8V	HSTL_I_18, HSTL_II_18	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.90
HSTL, Class III 1.8V	HSTL_III_18	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	1.08
SSTL (Stub Terminated Transceiver Logic), Class I & II, 3.3V	SSTL3_I, SSTL3_II	V_{REF} – 1.00	V_{REF} + 1.00	V_{REF}	1.5
SSTL, Class I & II, 2.5V	SSTL2_I, SSTL2_II	V_{REF} – 0.75	V_{REF} + 0.75	V_{REF}	1.25
SSTL, Class I & II, 1.8V	SSTL18_I, SSTL18_II	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.90
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	1.2 – 0.125	1.2 + 0.125	0(6)	–
LVDSEXT (LVDS Extended Mode), 2.5V	LVDSEXT_25	1.2 – 0.125	1.2 + 0.125	0(6)	–
HT (HyperTransport), 2.5V	LDT_25	0.6 – 0.125	0.6 + 0.125	0(6)	–

Notes:

1. The input delay measurement methodology parameters for LVDCI are the same for LVCMOS standards of the same voltage. Input delay measurement methodology parameters for HSLVDCI are the same as for HSTL_II standards of the same voltage. Parameters for all other DCI standards are the same for the corresponding non-DCI standards.
2. Input waveform switches between V_L and V_H.
3. Measurements are made at typical, minimum, and maximum V_{REF} values. Reported delays reflect worst case of these measurements. V_{REF} values listed are typical.
4. Input voltage level from which measurement starts.
5. This is an input voltage reference that bears no relation to the V_{REF} / V_{MEAS} parameters found in IBIS models and/or noted in Figure 6.
6. The value given is the differential input voltage.

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 55: **CLB Distributed RAM Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T_{SHCKO}	Clock to A – B outputs	0.92	1.10	1.36	1.49	ns, Max
T_{SHCKO_1}	Clock to AMUX – BMUX outputs	1.19	1.40	1.71	1.87	ns, Max
Setup and Hold Times Before/After Clock CLK						
T_{DS}/T_{DH}	A – D inputs to CLK	0.62/0.18	0.72/0.20	0.88/0.22	0.98/0.23	ns, Min
T_{AS}/T_{AH}	Address An inputs to clock	0.19/0.52	0.22/0.59	0.27/0.66	0.30/0.75	ns, Min
T_{WS}/T_{WH}	WE input to clock	0.27/0.00	0.32/0.00	0.40/0.00	0.47/–0.03	ns, Min
T_{CECK}/T_{CKCE}	CE input to CLK	0.28/–0.01	0.34/–0.01	0.41/–0.01	0.48/–0.05	ns, Min
Clock CLK						
T_{MPW}	Minimum pulse width	0.70	0.82	1.00	1.04	ns, Min
T_{MCP}	Minimum clock period	1.40	1.64	2.00	2.08	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 56: **CLB Shift Register Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T_{REG}	Clock to A – D outputs	1.11	1.30	1.58	1.74	ns, Max
T_{REG_MUX}	Clock to AMUX – DMUX output	1.37	1.60	1.93	2.12	ns, Max
T_{REG_M31}	Clock to DMUX output via M31 output	1.08	1.27	1.55	1.74	ns, Max
Setup and Hold Times Before/After Clock CLK						
T_{WS}/T_{WH}	WE input	0.05/0.00	0.07/0.00	0.09/0.00	0.11/0.03	ns, Min
T_{CECK}/T_{CKCE}	CE input to CLK	0.06/–0.01	0.08/–0.01	0.10/–0.01	0.12/0.02	ns, Min
T_{DS}/T_{DH}	A – D inputs to CLK	0.64/0.18	0.76/0.21	0.94/0.24	1.07/0.23	ns, Min
Clock CLK						
T_{MPW}	Minimum pulse width	0.60	0.70	0.85	0.89	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.

Block RAM and FIFO Switching Characteristics

Table 57: **Block RAM and FIFO Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Block RAM and FIFO Clock-to-Out Delays						
T_{RCKO_DO} and $T_{RCKO\_DO\_REG}$[1]	Clock CLK to DOUT output (without output register)[2][3]	1.60	1.79	2.08	2.36	ns, Max
	Clock CLK to DOUT output (with output register)[4][5]	0.60	0.66	0.75	0.83	ns, Max
$T_{RCKO\_DO\_ECC}$ and $T_{RCKO\_DO\_ECC\_REG}$	Clock CLK to DOUT output with ECC (without output register)[2][3]	2.62	2.89	3.30	3.73	ns, Max
	Clock CLK to DOUT output with ECC (with output register)[4][5]	0.71	0.77	0.86	0.94	ns, Max
T_{RCKO_CASC} and $T_{RCKO\_CASC\_REG}$	Clock CLK to DOUT output with Cascade (without output register)[2]	2.49	2.77	3.18	3.61	ns, Max
	Clock CLK to DOUT output with Cascade (with output register)[4]	1.29	1.41	1.58	1.79	ns, Max
T_{RCKO_FLAGS}	Clock CLK to FIFO flags outputs[6]	0.74	0.81	0.91	0.98	ns, Max
$T_{RCKO\_POINTERS}$	Clock CLK to FIFO pointers outputs[7]	0.90	0.98	1.09	1.21	ns, Max
$T_{RCKO\_SDBIT\_ECC}$ and $T_{RCKO\_SDBIT\_ECC\_REG}$	Clock CLK to BITERR (with output register)	0.62	0.68	0.76	0.82	ns, Max
	Clock CLK to BITERR (without output register)	2.21	2.46	2.84	3.23	ns, Max
$T_{RCKO\_PARITY\_ECC}$	Clock CLK to ECCPARITY in ECC encode only mode	0.86	0.94	1.06	1.18	ns, Max
$T_{RCKO\_RDADDR\_ECC}$ and $T_{RCKO\_RDADDR\_ECC\_REG}$	Clock CLK to RDADDR output with ECC (without output register)	0.73	0.79	0.90	1.00	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.76	0.82	0.92	1.02	ns, Max
Setup and Hold Times Before/After Clock CLK						
$T_{RCCK\_ADDR}/T_{RCKC\_ADDR}$	ADDR inputs[8]	0.47/ 0.27	0.53/ 0.29	0.62/ 0.32	0.66/ 0.34	ns, Min
T_{RDCK_DI}/T_{RCKD_DI}	DIN inputs[9]	0.84/ 0.30	0.95/ 0.32	1.11/ 0.34	1.26/ 0.36	ns, Min
$T_{RDCK\_DI\_ECC}/T_{RCKD\_DI\_ECC}$	DIN inputs with block RAM ECC in standard mode[9]	0.47/ 0.30	0.52/ 0.32	0.59/ 0.34	0.68/ 0.36	ns, Min
	DIN inputs with block RAM ECC encode only[9]	0.68/ 0.30	0.75/ 0.32	0.85/ 0.34	0.97/ 0.36	ns, Min
	DIN inputs with FIFO ECC in standard mode[9]	0.77/ 0.30	0.87/ 0.32	1.02/ 0.34	1.16/ 0.36	ns, Min
$T_{RCCK\_CLK}/T_{RCKC\_CLK}$	Inject single/double bit error in ECC mode	0.90/ 0.27	1.02/ 0.28	1.20/ 0.29	1.56/ 0.29	ns, Min
$T_{RCCK\_RDEN}/T_{RCKC\_RDEN}$	Block RAM Enable (EN) input	0.31/ 0.26	0.35/ 0.27	0.41/ 0.30	0.44/ 0.31	ns, Min
$T_{RCCK\_REGCE}/T_{RCKC\_REGCE}$	CE input of output register	0.18/ 0.25	0.19/ 0.27	0.22/ 0.31	0.24/ 0.33	ns, Min
$T_{RCCK\_RSTREG}/T_{RCKC\_RSTREG}$	Synchronous RSTREG input	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
$T_{RCCK\_RSTRAM}/T_{RCKC\_RSTRAM}$	Synchronous RSTRAM input	0.32/ 0.23	0.36/ 0.24	0.41/ 0.27	0.46/ 0.29	ns, Min

DSP48E1 Switching Characteristics

Table 58: **DSP48E1 Switching Characteristics**

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock							
$T_{DSPDCK\_\{A, ACIN; B, BCIN\}\_\{AREG; BREG\}}$/ $T_{DSPCKD\_\{A, ACIN; B, BCIN\}\_\{AREG; BREG\}}$	{A, ACIN, B, BCIN} input to {A, B} register CLK	0.25/ 0.27	0.29/ 0.30	0.35/ 0.34	0.36/ 0.34	0.46/ 0.39	ns
$T_{DSPDCK\_C\_CREG}$/$T_{DSPCKD\_C\_CREG}$	C input to C register CLK	0.16/ 0.20	0.19/ 0.22	0.22/ 0.24	0.25/ 0.24	0.33/ 0.30	ns
$T_{DSPDCK\_D\_DREG}$/$T_{DSPCKD\_D\_DREG}$	D input to D register CLK	0.07/ 0.31	0.10/ 0.34	0.15/ 0.39	0.16/ 0.39	0.24/ 0.45	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock							
$T_{DSPDCK\_\{A, ACIN, B, BCIN\}\_MREG\_MULT}$/ $T_{DSPCKD\_\{A, ACIN, B, BCIN\}\_MREG\_MULT}$	{A, ACIN, B, BCIN} input to M register CLK	2.36/ 0.04	2.70/ 0.04	3.21/ 0.04	3.21/ 0.04	3.66/ 0.02	ns
$T_{DSPDCK\_\{A, D\}\_ADREG}$/ $T_{DSPCKD\_\{A, D\}\_ADREG}$	{A, D} input to AD register CLK	1.24/ 0.10	1.42/ 0.12	1.69/ 0.13	1.69/ 0.13	1.91/ 0.16	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock							
$T_{DSPDCK\_\{A, ACIN, B, BCIN\}\_PREG\_MULT}$/ $T_{DSPCKD\_\{A, ACIN, B, BCIN\}\_PREG\_MULT}$	{A, ACIN, B, BCIN} input to P register CLK using multiplier	3.83/ –0.13	4.37/ –0.13	5.20/ –0.13	5.20/ –0.13	5.94/ –0.24	ns
$T_{DSPDCK\_D\_PREG\_MULT}$/ $T_{DSPCKD\_D\_PREG\_MULT}$	D input to P register CLK	3.62/ –0.47	4.13/ –0.47	4.90/ –0.47	4.90/ –0.47	5.61/ –0.77	ns
$T_{DSPDCK\_\{A, ACIN, B, BCIN\}\_PREG}$/ $T_{DSPCKD\_\{A, ACIN, B, BCIN\}\_PREG}$	{A, ACIN, B, BCIN} input to P register CLK not using multiplier	1.59/ –0.13	1.81/ –0.13	2.15/ –0.13	2.15/ –0.13	2.44/ –0.24	ns
$T_{DSPDCK\_C\_PREG}$/ $T_{DSPCKD\_C\_PREG}$	C input to P register CLK	1.42/ –0.10	1.61/ –0.10	1.91/ –0.10	1.91/ –0.10	2.16/ –0.19	ns
$T_{DSPDCK\_\{PCIN, CARRYCASCIN, MULTSIGNIN\}\_PREG}$/ $T_{DSPCKD\_\{PCIN, CARRYCASCIN, MULTSIGNIN\}\_PREG}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to P register CLK	1.23/ –0.02	1.41/ –0.02	1.67/ –0.02	1.67/ –0.02	1.91/ –0.07	ns
Setup and Hold Times of the CE Pins							
$T_{DSPDCK\_\{CEA; CEB\}\_\{AREG; BREG\}}$/ $T_{DSPCKD\_\{CEA; CEB\}\_\{AREG; BREG\}}$	{CEA; CEB} input to {A; B} register CLK	0.14/ 0.19	0.17/ 0.22	0.22/ 0.25	0.22/ 0.25	0.30/ 0.28	ns
$T_{DSPDCK\_CEC\_CREG}$/ $T_{DSPCKD\_CEC\_CREG}$	CEC input to C register CLK	0.15/ 0.18	0.18/ 0.20	0.24/ 0.23	0.24/ 0.23	0.31/ 0.26	ns
$T_{DSPDCK\_CED\_DREG}$/ $T_{DSPCKD\_CED\_DREG}$	CED input to D register CLK	0.20/ 0.12	0.24/ 0.13	0.31/ 0.14	0.31/ 0.14	0.43/ 0.16	ns
$T_{DSPDCK\_CEM\_MREG}$/ $T_{DSPCKD\_CEM\_MREG}$	CEM input to M register CLK	0.16/ 0.19	0.20/ 0.21	0.26/ 0.25	0.26/ 0.25	0.32/ 0.28	ns
$T_{DSPDCK\_CEP\_PREG}$/ $T_{DSPCKD\_CEP\_PREG}$	CEP input to P register CLK	0.32/ 0.02	0.38/ 0.02	0.46/ 0.03	0.46/ 0.03	0.54/ 0.04	ns
Setup and Hold Times of the RST Pins							
$T_{DSPDCK\_\{RSTA; RSTB\}\_\{AREG; BREG\}}$/ $T_{DSPCKD\_\{RSTA; RSTB\}\_\{AREG; BREG\}}$	{RSTA, RSTB} input to {A, B} register CLK	0.27/ 0.17	0.31/ 0.19	0.38/ 0.22	0.38/ 0.22	0.41/ 0.25	ns
$T_{DSPDCK\_RSTC\_CREG}$/ $T_{DSPCKD\_RSTC\_CREG}$	RSTC input to C register CLK	0.18/ 0.08	0.20/ 0.08	0.23/ 0.09	0.23/ 0.09	0.27/ 0.11	ns
$T_{DSPDCK\_RSTD\_DREG}$/ $T_{DSPCKD\_RSTD\_DREG}$	RSTD input to D register CLK	0.28/ 0.15	0.32/ 0.16	0.38/ 0.19	0.38/ 0.19	0.45/ 0.21	ns
$T_{DSPDCK\_RSTM\_MREG}$/ $T_{DSPCKD\_RSTM\_MREG}$	RSTM input to M register CLK	0.20/ 0.24	0.23/ 0.26	0.26/ 0.30	0.26/ 0.30	0.29/ 0.34	ns

Table 58: **DSP48E1 Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
$T_{DSPDO\_\{PCIN, CARRYCASCIN, MULTSIGNIN\}\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.28	1.46	1.72	1.72	2.06	ns
Clock to Outs from Output Register Clock to Output Pins							
$T_{DSPCKO\_\{P, CARRYOUT\}\_PREG}$	CLK (PREG) to {P, CARRYOUT} output	0.38	0.43	0.50	0.50	0.57	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_PREG}$	CLK (PREG) to {CARRYCASCOUT, PCOUT, MULTSIGNOUT} output	0.50	0.56	0.66	0.66	0.76	ns
Clock to Outs from Pipeline Register Clock to Output Pins							
$T_{DSPCKO\_\{P, CARRYOUT\}\_MREG}$	CLK (MREG) to {P, CARRYOUT} output	1.72	1.96	2.30	2.30	2.69	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_MREG}$	CLK (MREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.81	2.06	2.43	2.43	2.88	ns
$T_{DSPCKO\_\{P, CARRYOUT\}\_ADREG\_MULT}$	CLK (ADREG) to {P, CARRYOUT} output	2.79	3.16	3.72	3.72	4.32	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_ADREG\_MULT}$	CLK (ADREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	2.87	3.26	3.84	3.84	4.51	ns
Clock to Outs from Input Register Clock to Output Pins							
$T_{DSPCKO\_\{P, CARRYOUT\}\_\{AREG, BREG\}\_MULT}$	CLK (AREG, BREG) to {P, CARRYOUT} output using multiplier	3.97	4.52	5.36	5.36	6.20	ns
$T_{DSPCKO\_\{P, CARRYOUT\}\_\{AREG, BREG\}}$	CLK (AREG, BREG) to {P, CARRYOUT} output not using multiplier	1.70	1.93	2.27	2.27	2.65	ns
$T_{DSPCKO\_\{P, CARRYOUT\}\_CREG}$	CLK (CREG) to {P, CARRYOUT} output	1.70	1.93	2.27	2.27	2.80	ns
$T_{DSPCKO\_\{P, CARRYOUT\}\_DREG\_MULT}$	CLK (DREG) to {P, CARRYOUT} output	3.89	4.44	5.25	5.25	6.07	ns
Clock to Outs from Input Register Clock to Cascading Output Pins							
$T_{DSPCKO\_\{ACOUT; BCOUT\}\_\{AREG; BREG\}}$	CLK (AREG, BREG) to {P, CARRYOUT} output	0.66	0.76	0.89	0.89	1.01	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_\{AREG, BREG\}\_MULT}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	4.05	4.63	5.49	5.49	6.39	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_\{AREG, BREG\}}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output not using multiplier	1.79	2.03	2.40	2.40	2.84	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_DREG\_MULT}$	CLK (DREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	3.98	4.54	5.38	5.38	6.26	ns
$T_{DSPCKO\_\{PCOUT, CARRYCASCOUT, MULTSIGNOUT\}\_CREG}$	CLK (CREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.78	2.03	2.40	2.40	2.99	ns

Table 66: **Global Clock Input to Output Delay With MMCM**

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, *with* MMCM.							
$T_{ICKOFMMCMGC}$	Global Clock Input and OUTFF *with* MMCM	XC6VLX75T	2.34	2.50	2.77	2.85	ns
		XC6VLX130T	2.35	2.51	2.78	2.87	ns
		XC6VLX195T	2.36	2.52	2.79	2.88	ns
		XC6VLX240T	2.36	2.52	2.79	2.88	ns
		XC6VLX365T	2.37	2.53	2.79	2.89	ns
		XC6VLX550T	N/A	2.55	2.82	2.93	ns
		XC6VLX760	N/A	2.54	2.82	2.92	ns
		XC6VSX315T	2.35	2.51	2.79	2.87	ns
		XC6VSX475T	N/A	2.43	2.70	2.79	ns
		XC6VHX250T	2.36	2.53	2.80	N/A	ns
		XC6VHX255T	2.46	2.63	2.91	N/A	ns
		XC6VHX380T	2.39	2.59	2.83	N/A	ns
		XC6VHX565T	N/A	2.54	2.81	N/A	ns
		XQ6VLX130T	N/A	2.51	2.78	2.87	ns
		XQ6VLX240T	N/A	2.52	2.79	2.88	ns
		XQ6VLX550T	N/A	N/A	2.82	2.93	ns
		XQ6VSX315T	N/A	2.51	2.79	2.87	ns
		XQ6VSX475T	N/A	N/A	2.70	2.79	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 70: **Clock-Capable Clock Input Setup and Hold With MMCM**

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Clock-capable Clock Input Signal for LVCMOS25 Standard.(1)							
$T_{PSMMCMCC}$/ $T_{PHMMCMCC}$	No Delay Clock-capable Clock Input and IFF(2) with MMCM	XC6VLX75T	1.56/ –0.25	1.69/ –0.25	1.86/ –0.25	1.91/ –0.15	ns
		XC6VLX130T	1.64/ –0.25	1.78/ –0.25	1.95/ –0.25	2.00/ –0.14	ns
		XC6VLX195T	1.65/ –0.24	1.79/ –0.24	1.96/ –0.24	2.01/ –0.15	ns
		XC6VLX240T	1.65/ –0.24	1.79/ –0.24	1.96/ –0.24	2.01/ –0.15	ns
		XC6VLX365T	1.66/ –0.25	1.79/ –0.25	1.97/ –0.25	2.02/ –0.15	ns
		XC6VLX550T	N/A	1.97/ –0.24	2.16/ –0.24	2.19/ –0.14	ns
		XC6VLX760	N/A	2.39/ –0.20	2.63/ –0.20	2.21/ –0.10	ns
		XC6VSX315T	1.67/ –0.25	1.80/ –0.25	1.98/ –0.25	2.03/ –0.16	ns
		XC6VSX475T	N/A	1.98/ –0.29	2.17/ –0.29	2.21/ –0.20	ns
		XC6VHX250T	1.63/ –0.24	1.76/ –0.24	1.94/ –0.24	N/A	ns
		XC6VHX255T	1.63/ –0.19	1.76/ –0.19	1.99/ –0.19	N/A	ns
		XC6VHX380T	1.80/ –0.23	1.94/ –0.23	2.13/ –0.23	N/A	ns
		XC6VHX565T	N/A	1.94/ –0.08	2.13/ –0.08	N/A	ns
		XQ6VLX130T	N/A	1.78/ –0.25	1.95/ –0.25	2.00/ –0.14	ns
		XQ6VLX240T	N/A	1.79/ –0.24	1.96/ –0.24	2.01/ –0.15	ns
		XQ6VLX550T	N/A	N/A	2.16/ –0.24	2.19/ –0.14	ns
		XQ6VSX315T	N/A	1.80/ –0.25	1.98/ –0.25	2.03/ –0.16	ns
		XQ6VSX475T	N/A	N/A	2.17/ –0.29	2.21/ –0.20	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.